

DOCKET NO: 116120US2



IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF : DATE ALLOWED: 03/22/06
SHIGENOBU MAEDA, ET AL. : EXAMINER: CRANE, S.W.
SERIAL NO: 09/176,315 :
FILED: OCTOBER 22, 1998 : GROUP ART UNIT: 2811
FOR: METHOD OF DESIGNING :
SEMICONDUCTOR DEVICE,
SEMICONDUCTOR DEVICE AND
RECORDING MEDIUM

PETITION UNDER 37 CFR §1.181(a)(3)

COMMISSIONER FOR PATENTS
Alexandria, Virginia 22313

SIR:

This is a Petition pursuant to 37 CFR §1.181(a)(3) requesting that the examiner supply Applicants a copy of the below noted Form PTO-1449 that properly indicates, by the examiner's initials, consideration of all the references listed thereon.

STATEMENT OF FACTS

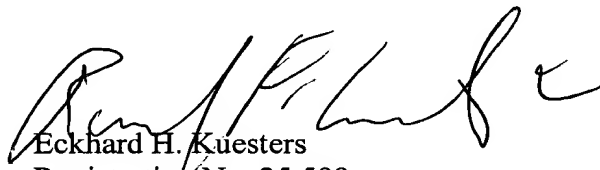
On March 5, 2003, Information Disclosure Statement (IDS) papers were filed that included a Form PTO-1449 listing five references ("AA," AP," "AQ," "AX," and "AY") for consideration as documented by the attached copy of these IDS papers including the Form PTO-1449 and the associated date-stamped mail room filing receipt. No indication of consideration of references "AX" or "AY" has been received as is clear from the attached copy of the Form PTO-1449 that was attached to the Advisory Action mailed May 5, 2003, and contains Examiner initials only next to references "AA," AP," and "AQ. "

ACTION REQUESTED

It is respectfully requested that the Examiner provide Applicants a copy of the above-noted Form PTO-1449 filed with the above-noted IDS papers on March 3, 2005, that properly acknowledges with the examiner's initials the consideration of references "AX" and "AY" listed thereon.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.



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Dept.: E/M

OSMM&N File No. 0057-2362-2YY

By: GJM/RFC/jmp

Serial No. 09/176,315

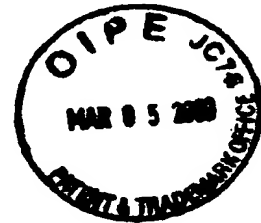
In the matter of the Application of: SHIGENOBU MAEDA, ET AL.

For: METHOD OF DESIGNING SEMICONDUCTOR DEVICE,
SEMICONDUCTOR DEVICE AND RECORDING MEDIUM

Due Date: 03/05/03

The following has been received in the U.S. Patent Office on the date stamped hereon:

- ☒ Check for \$180.00
- ☒ Dep. Acct. Order Form
- ☒ Information Disclosure Statement
- ☒ Cited References (5)
- ☒ German Office Action with English Translations & Abstract
- ☒ PTO 1449



724

Docket No. 0057-2362-2YY



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: SHIGENOBU MAEDA, ET AL.

SERIAL NO: 09/176,315

GAU: 2811

FILED: OCTOBER 22, 1998

EXAMINER: CRANE, S.

FOR: METHOD OF DESIGNING SEMICONDUCTOR DEVICE, SEMICONDUCTOR DEVICE AND RECORDING MEDIUM

INFORMATION DISCLOSURE/RELATED CASE STATEMENT UNDER 37 CFR 1.97

ASSISTANT COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references cited in German Office Action and which are listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☒ A check is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☒ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
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Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
0057-2362-2YYSERIAL NO.
09/176,315

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

SHIGENOBU MAEDA, ET AL.

FILED

OCTOBER 22, 1998

GROUP

2811

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	4,946,799	08/07/90	Blake et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AP	DE 196 23 846 A1	04/17/97	Germany		x
	AQ	DE 44 41 901 A1	05/30/98	Germany		x
	AR					
	AS					
	AT					
	AU					
	AV					
	AW					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AX	Modulationsdotierte Feldeffekttransistoren; Heiner HeiB; Dissertaton am Lehrstuhl für Halbleitertechnologie der TU München; eingereicht am 31.10.1996, pages 59 to 69 (with English abstract)
	AY	Schumicki, Seegebrecht; Prozesstechnologie; paes 404 to 436; ; Springer Verlag; 1991 (with English abstract)
	AZ	
	AZ	

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.